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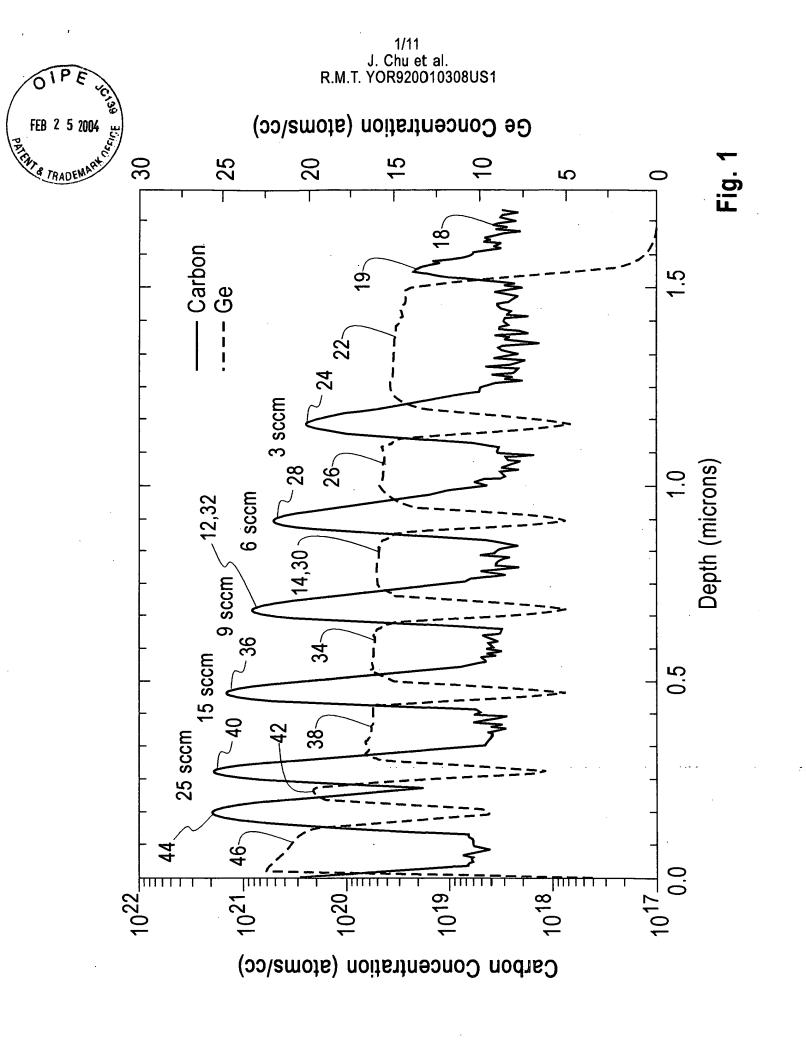
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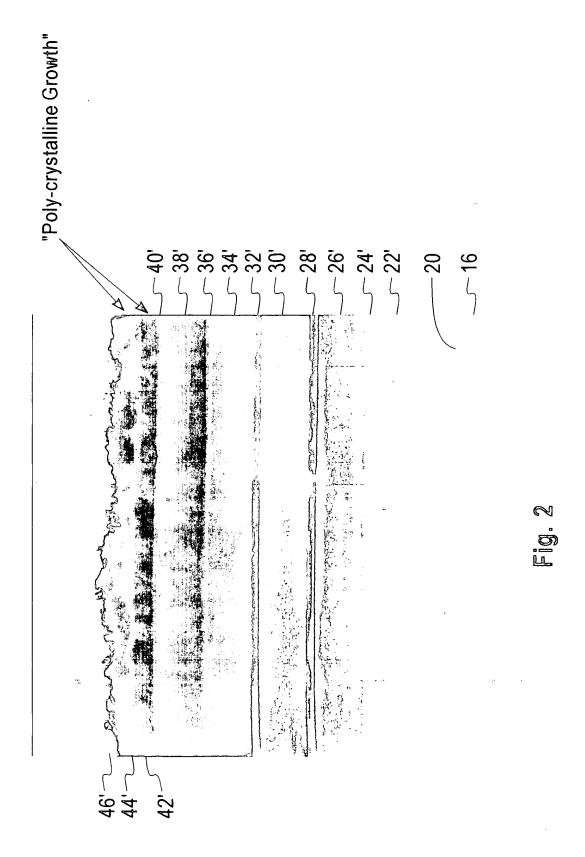
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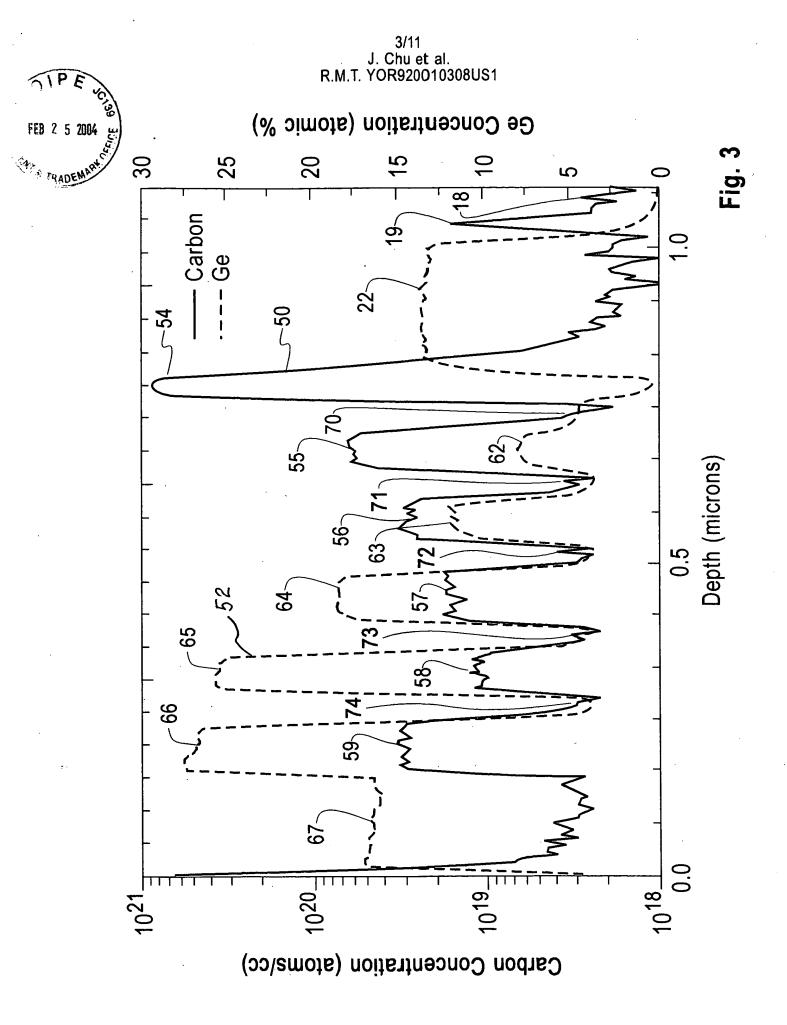
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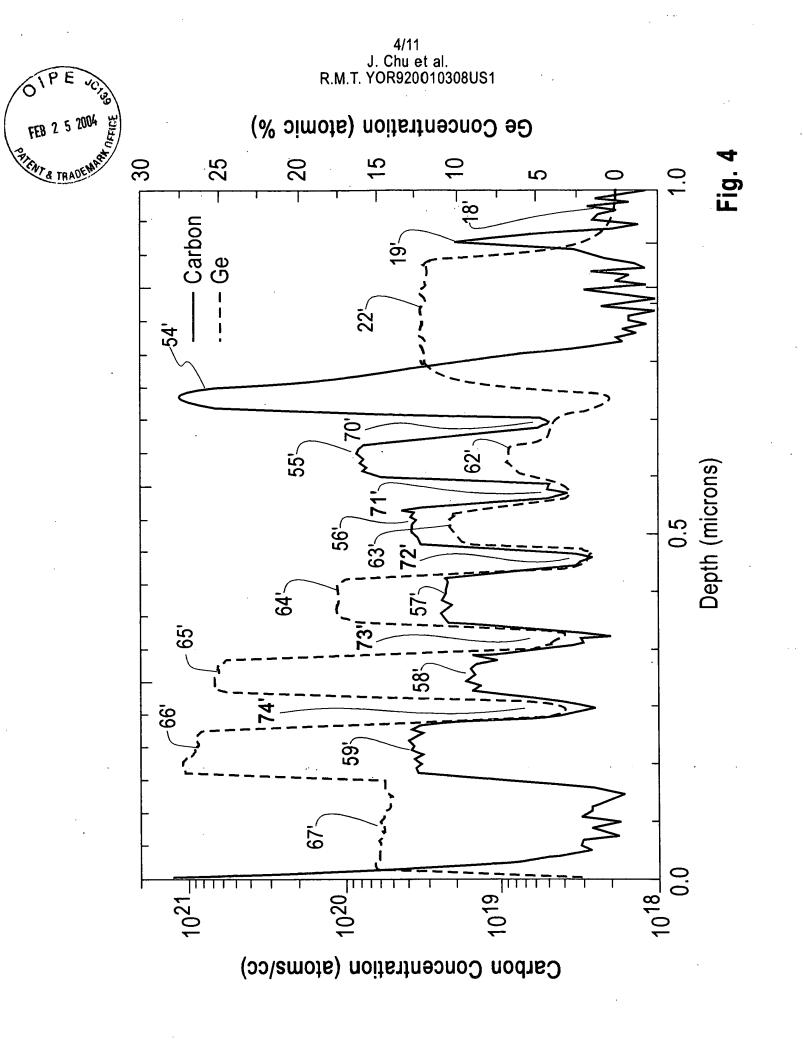
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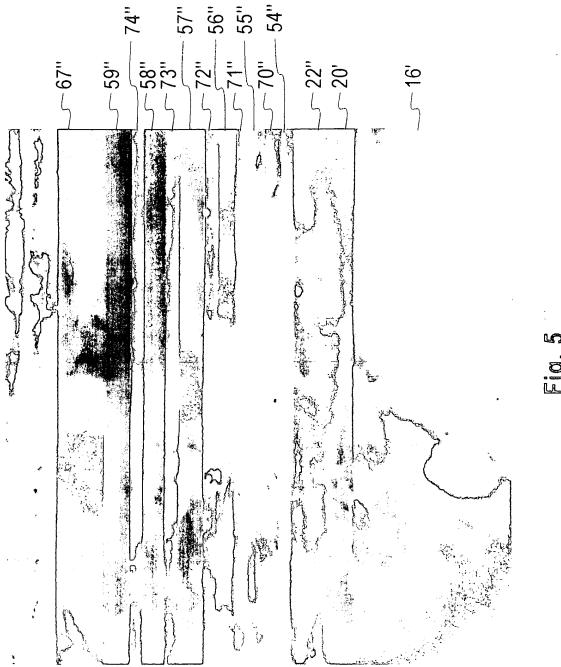


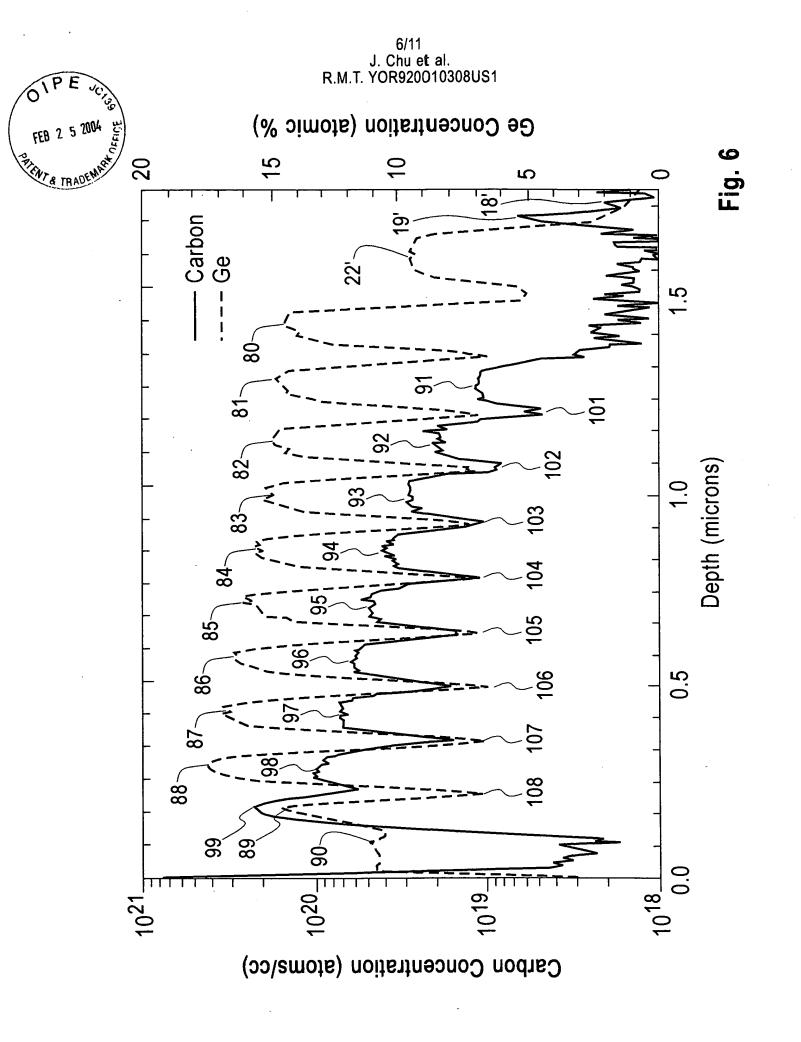
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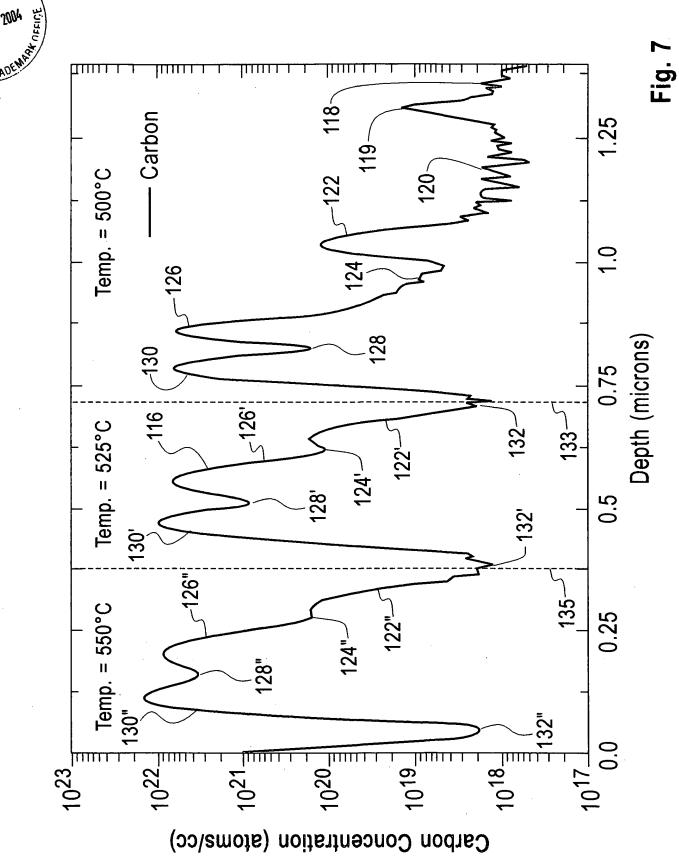




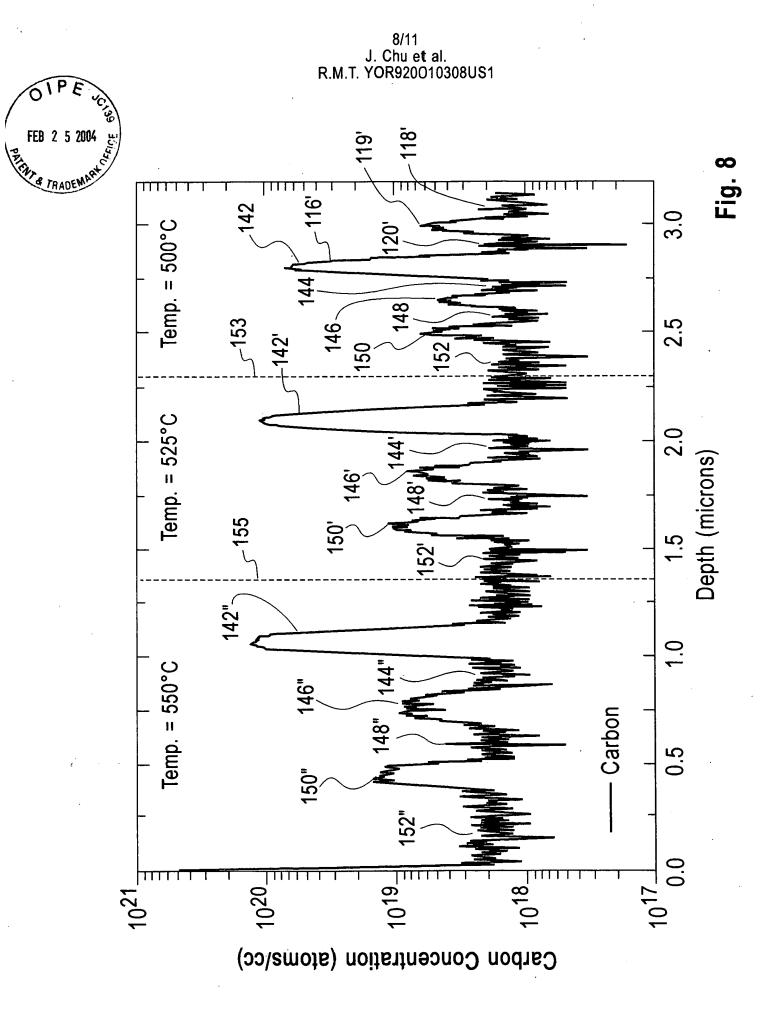




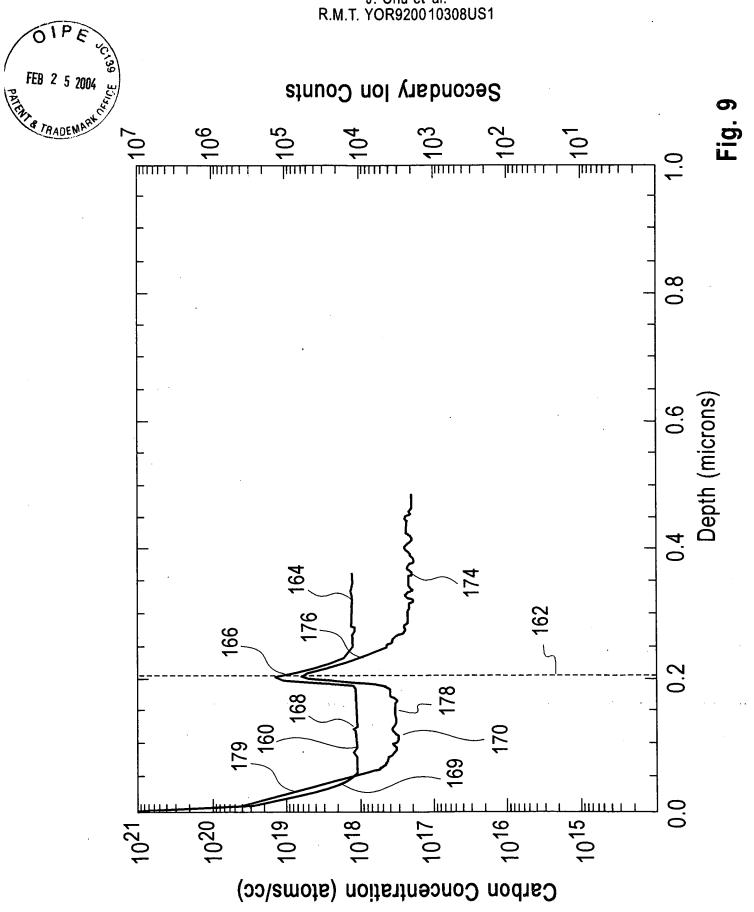
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10/11 J. Chu et al. R.M.T. YOR920010308US1 Ge Concentration (atomic %) FEB 2 5 2004 TRADEMARKE Fig. 10 ~ 9 Carbon Boron 180 98 9.0 SiGeB w/o Carbon 198 Depth (microns) 199 196~ SiGeB:C 200 208 210 212 <u>لے بی سال</u> 1021 Carbon & Boron Concentration (atoms/cc)

